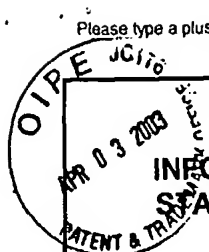


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Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Application Number	10/062,992
				Filing Date	1/31/02
				First Named Inventor	Steven Teig, et al.
				Group Art Unit	2121
				Examiner Name	
Sheet	1	of	2	Attorney Docket Number	SPLX.P0096

RELATED U.S. PATENT APPLICATIONS					
Examiner Initials	Cite No. ¹	U.S. Patent Application	Name of Patentee or Applicant of Cited Document	Date of Filing MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Serial Number			
<div style="text-align: center;"> </div>	1.	10/062,017	Steven Teig & Asmus Hetzel	01-31-02	
	2.	10/061,459	Steven Teig & Asmus Hetzel	01-31-02	
	3.	10/062,014	Steven Teig & Asmus Hetzel	01-31-02	
	4.	10/062,044	Steven Teig & Asmus Hetzel	01-31-02	
	5.	10/066,264	Steven Teig & Asmus Hetzel	01-31-02	
	6.	10/066,188	Steven Teig & Asmus Hetzel	01-31-02	
	7.	10/061,474	Steven Teig & Asmus Hetzel	01-31-02	
	8.	10/061,719	Steven Teig & Asmus Hetzel	01-31-02	
	9.	10/066,456	Steven Teig & Asmus Hetzel	01-31-02	
	10.	10/062,993	Steven Teig & Asmus Hetzel	01-31-02	
	11.	10/062,047	Steven Teig & Asmus Hetzel	01-31-02	

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U.S. PATENT DOCUMENTS						
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		Number	Kind Code ² (if known)			
<i>KSL</i>	12.	5,649,165		Jain et al.	07-15-97	
<i>KSL</i>	13.	6,301,687	B1	Jain et al.	10-09-01	

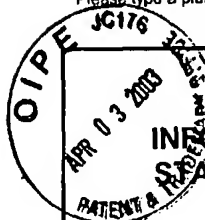
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				Group Art Unit	2121
				Examiner Name	
Sheet	2	of	2	Attorney Docket Number	SPLX.P0096

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS					
Examiner* Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
↑	14.	D. Jongeneel, R. Otten, Y. Watanabe and R. K. Brayton, Area and Search Space Control for Technology Mapping, 37 th Design Automation Conference, 86-91, 2000.			
	15.	Henrik Reif Andersen, An Introduction to Binary Decision Diagrams, October 1997 (minor revisions April 1998), 36 pp.			
	16.	Jerry Burch and David Long, Efficient Boolean Function Matching, Proc. ICCAD 1992, 408-411.			
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	18.	Kamal Chaudhary and Massoud Pedram, A Near Optimal Algorithm for Technology Mapping Minimizing Area under Delay Constraints, Proceedings of the 29 th Design Automation Conference, 492-498, 1992.			
	19.	Kurt Keutzer, DAGON: Technology Binding and Local Optimization by DAG Matching, Proceedings of the 24 th Design Automation Conference, 341-347, 1987			
	20.	Randal Bryant, Symbolic Boolean Manipulation with Ordered Binary Decision Diagrams, CMU CS Tech Report CMU-CS-92-160.			
	21.	Uwe Hinsberger and Reiner Kolla, Boolean Matching for Large Libraries, Proceedings of the 35 th Design Automation Conference, 206-211, June 1998.			
	22.	Yuji Kukimoto, Robert K. Brayton, and Prashant Sawkar, Delay-Optimal Technology Mapping by DAG Covering, Dept. of Electrical Engineering and Computer Science, University of California, Berkeley, Strategic CAD Laboratories, Intel Corp., October 1997.			
	23.	Zbigniew J. Czech, et al., An Optimal Algorithm for Generating Minimal Perfect Hashing Functions, Information Processing Letters, 43(5); 257-264, October 1992			

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